

N-channel 600 V, 1.7 Ω typ., 4 A Zener-protected SuperMESH™
Power MOSFETs in D²PAK, I²PAK, DPAK and IPAK packages

Datasheet - production data

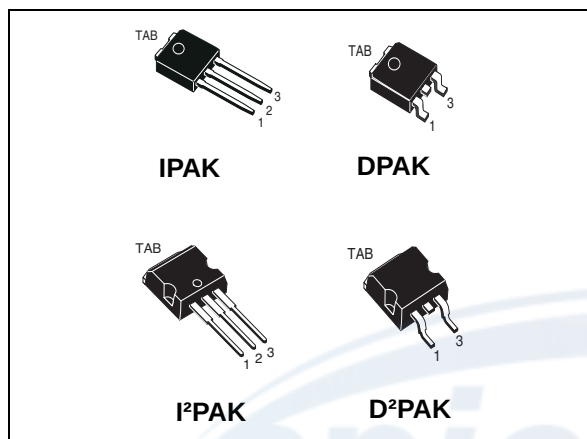
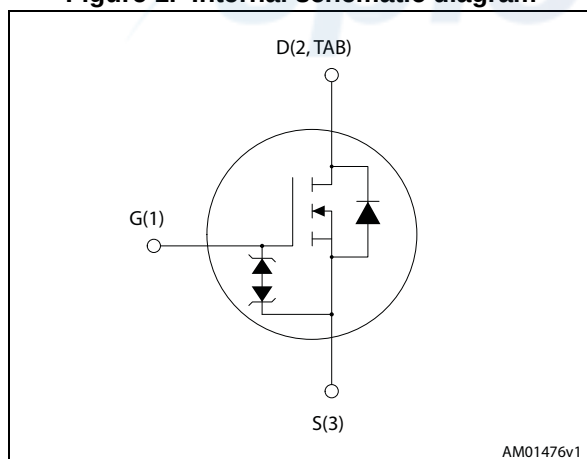


Figure 1. Internal schematic diagram



Features

Order codes	V _{DS}	R _{DS(on)} max.	P _{TOT}	I _D
STB4NK60ZT4	600 V	2 Ω	70 W	4 A
STB4NK60Z-1				
STD4NK60ZT4				
STD4NK60Z-1				

- 100% avalanche tested
- Very low intrinsic capacitances
- Zener-protected

Applications

- Switching applications

Description

These devices are N-channel Zener-protected Power MOSFETs developed using STMicroelectronics' SuperMESH™ technology, achieved through optimization of ST's well established strip-based PowerMESH™ layout. In addition to a significant reduction in on-resistance, this device is designed to ensure a high level of dv/dt capability for the most demanding applications.

Table 1. Device summary

Order codes	Marking	Packages	Packaging
STB4NK60ZT4	B4NK60Z	D ² PAK	Tape and reel
STB4NK60Z-1		I ² PAK	Tube
STD4NK60ZT4	D4NK60Z	DPAK	Tape and reel
STD4NK60Z-1		IPAK	Tube

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1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V_{GS}	Gate- source voltage	± 30	V
I_D	Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$	4	A
I_D	Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$	2.5	A
$I_{DM}^{(1)}$	Drain current (pulsed)	16	A
P_{TOT}	Total dissipation at $T_C = 25\text{ }^{\circ}\text{C}$	70	W
	Derating factor	0.56	W/ $^{\circ}\text{C}$
ESD	Gate-source human body model (C=100 pF, R=1.5 k Ω)	3	kV
$dv/dt^{(2)}$	Peak diode recovery voltage slope	4.5	V/ns
T_{stg}	Storage temperature	-55 to 150	$^{\circ}\text{C}$
T_J	Max operating junction temperature	150	$^{\circ}\text{C}$

1. Pulse width limited by safe operating area

2. $I_{SD} \leq 4\text{ A}$, $di/dt \leq 200\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq T_{JMAX}$.

Table 3. Thermal data

Symbol	Parameter	Value		Unit
		D ² PAK, I ² PAK	DPAK, IPAK	
$R_{thj-case}$	Thermal resistance junction-case max	1.79		$^{\circ}\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5	100	$^{\circ}\text{C}/\text{W}$

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_{Jmax})	4	A
E_{AS}	Single pulse avalanche energy (starting $T_J = 25\text{ }^{\circ}\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$)	120	mJ

2 Electrical characteristics

($T_{CASE} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1\text{ mA}$	600			V
I_{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	$V_{DS} = 600\text{ V}$ $V_{DS} = 600\text{ V}, T_C = 125\text{ }^{\circ}\text{C}$			1 50	μA μA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$)	$V_{GS} = \pm 20\text{ V}$			± 10	μA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 50\text{ }\mu\text{A}$	3	3.75	4.5	V
$R_{DS(on)}$	Static drain-source on resistance	$V_{GS} = 10\text{ V}, I_D = 2\text{ A}$		1.7	2	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$g_{fs}^{(1)}$	Forward transconductance	$V_{DS} = 15\text{ V}, I_D = 2\text{ A}$	-	3		S
C_{iss}	Input capacitance	$V_{DS} = 25\text{ V}, f = 1\text{ MHz},$ $V_{GS} = 0$	-	510		pF
C_{oss}	Output capacitance		-	67		pF
C_{rss}	Reverse transfer capacitance		-	13		pF
$C_{oss\text{ eq.}}^{(2)}$	Equivalent output capacitance	$V_{DS} = 0, V_{DS} = 0\text{ to }480\text{ V}$	-	38.5		pF
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300\text{ V}, I_D = 2\text{ A},$ $R_G = 4.7\text{ }\Omega, V_{GS} = 10\text{ V}$ (see Figure 15)	-	12		ns
t_r	Rise time		-	9.5		ns
$t_{d(off)}$	Turn-off delay time		-	29		ns
t_f	Fall time		-	16.5		ns
$t_{r(Voff)}$	Off-voltage rise time	$V_{DD} = 480\text{ V}, I_D = 4\text{ A},$ $R_G = 4.7\text{ }\Omega, V_{GS} = 10\text{ V}$ (see Figure 17)	-	12		ns
t_f	Fall time		-	12		ns
t_c	Cross-over time		-	19.5		ns
Q_g	Total gate charge	$V_{DD} = 480\text{ V}, I_D = 4\text{ A},$ $V_{GS} = 10\text{ V}$ (see Figure 16)	-	18.8	26	nC
Q_{gs}	Gate-source charge		-	3.8		nC
Q_{gd}	Gate-drain charge		-	9.8		nC

1. Pulsed: pulse duration=300 μs , duty cycle 1.5%

2. $C_{oss\text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		4	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		16	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 4\text{ A}$, $V_{GS} = 0$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 4\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$	-	400		ns
Q_{rr}	Reverse recovery charge	$V_{DD} = 24\text{ V}$, $T_j = 150\text{ }^\circ\text{C}$	-	1700		nC
I_{RRM}	Reverse recovery current	(see Figure 17)	-	8.5		A

1. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2. Pulse width limited by safe operating area

Table 8. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min	Typ.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1\text{ mA}$, $I_D = 0$	30	-	-	V

The built-in back-to-back Zener diodes have been specifically designed to enhance not only the device's ESD capability, but also to make them capable of safely absorbing any voltage transients that may occasionally be applied from gate to source. In this respect, the Zener voltage is appropriate to achieve efficient and cost-effective protection of device integrity. The integrated Zener diodes thus eliminate the need for external components.

Figure 2. Safe operating area

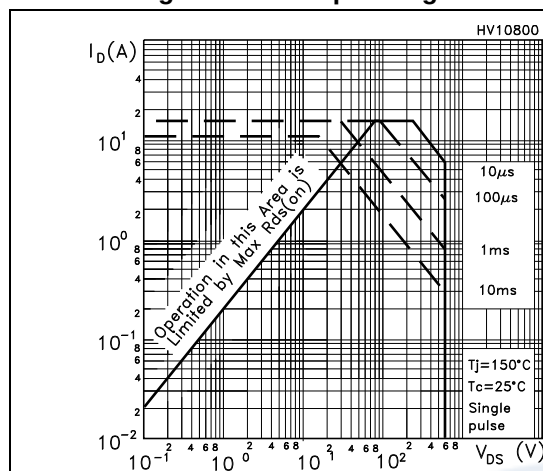


Figure 1 is a log-log plot showing the normalized temperature rise K (Y-axis, ranging from 10^{-2} to 10^0) versus the pulse width t_p (X-axis, ranging from 10^{-5} to 10^0 s). The plot displays several curves corresponding to different values of the parameter δ : 0.5, 0.2, 0.1, 0.05, 0.02, and 0.01. The curves show that K increases with t_p and decreases with δ . An inset diagram illustrates a single pulse waveform with pulse width t_p and period τ . The inset also contains the equations $Z_{th} = k R_{thJ-c}$ and $\delta = t_p / \tau$.

Figure 1 is a graph showing the Drain current (I_D) in Amperes (A) versus the Drain-Source Voltage (V_{DS}) in Volts (V) for the HV10820 MOSFET. The graph is plotted for a constant Gate-Source Voltage (V_{GS}) of 10V. The x-axis (V_{DS}) ranges from 0 to 25V, and the y-axis (I_D) ranges from 0 to 8A. The graph displays several curves for different Gate-Source Voltages (V_{GS}), with the curves for 8V and 9V highlighted by a blue box.

V_{DS} (V)	I_D (A) at $V_{GS}=5V$	I_D (A) at $V_{GS}=6V$	I_D (A) at $V_{GS}=7V$	I_D (A) at $V_{GS}=8V$	I_D (A) at $V_{GS}=9V$
0	0.0	0.0	0.0	0.0	0.0
5	0.2	0.8	1.8	3.2	4.2
10	0.3	1.2	2.8	5.0	6.2
15	0.4	1.4	3.2	6.2	7.2
20	0.5	1.5	3.4	6.8	7.8
25	0.6	1.6	3.5	7.2	8.2

Transfer characteristic graph showing Drain Current (I_D) in Amperes (A) versus Gate-Source Voltage (V_{GS}) in Volts (V) for the HV10825 MOSFET. The graph is plotted at a constant Drain-Source Voltage (V_{DS}) of 25V.

The Y-axis (I_D) ranges from 0 to 8 A, and the X-axis (V_{GS}) ranges from 0 to 10 V. The curve shows that the drain current remains near zero until V_{GS} reaches approximately 4.5V, after which it increases sharply, reaching a saturation region around 8A for V_{GS} values above 7.5V.

V_{GS} (V)	I_D (A)
0	0.0
2	0.0
4	0.0
4.5	0.1
5	0.5
5.5	1.5
6	3.5
6.5	6.0
7	7.5
7.5	7.8
8	7.9
9	8.0
10	8.1

Figure 1 is a graph showing the transfer characteristics of the HV10670 device. The y-axis represents the transconductance g_{rs} in Siemens (S), ranging from 0 to 10. The x-axis represents the drain current I_D in Amperes (A), ranging from 0 to 8. The graph is for a constant drain-source voltage $V_{DS} = 15V$. Three curves are plotted for different temperatures T_J : $-50^\circ C$, $25^\circ C$, and $150^\circ C$. The curves show that g_{rs} increases with I_D and decreases with increasing temperature.

I_D (A)	g_{rs} (S) at $-50^\circ C$	g_{rs} (S) at $25^\circ C$	g_{rs} (S) at $150^\circ C$
1.0	3.5	3.0	2.2
2.0	5.0	4.2	3.0
4.0	6.5	5.5	4.2
6.0	7.5	6.5	-
8.0	8.2	7.0	-

Graph showing the on-state resistance $R_{DS(on)}$ (in Ω) versus the drain current I_D (in A) for the HV10840 MOSFET at $V_{GS} = 10V$. The resistance increases with current.

I_D (A)	$R_{DS(on)}$ (Ω)
0.5	1.58
1.0	1.62
1.5	1.66
2.0	1.70
2.5	1.75
3.0	1.80
3.5	1.85
4.0	1.90

Figure 8. Gate charge vs gate-source voltage

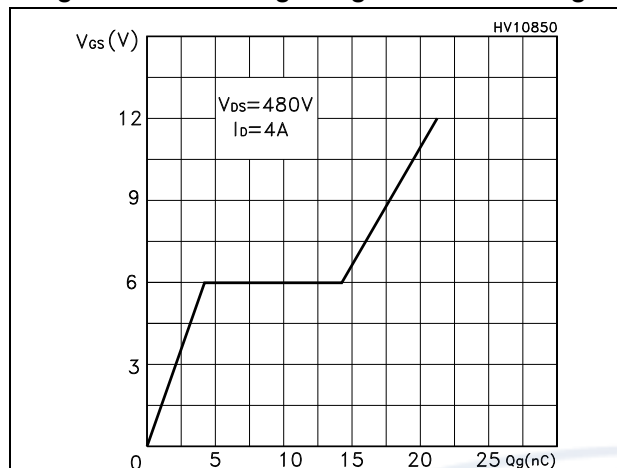


Figure 9. Capacitance variations

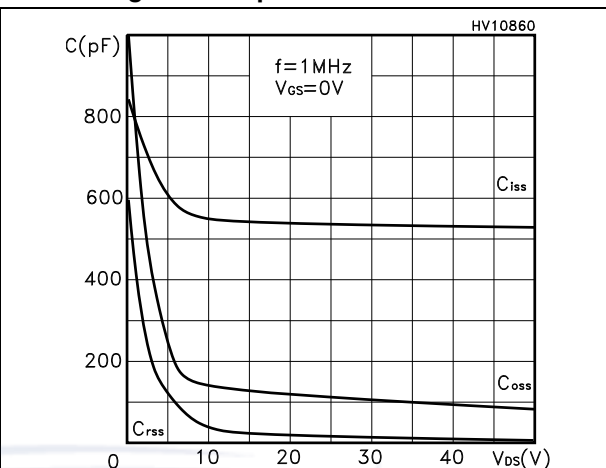


Figure 10. Normalized gate threshold voltage vs temperature

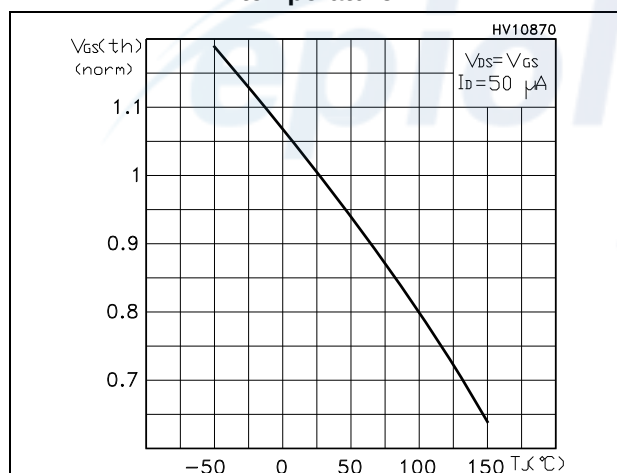
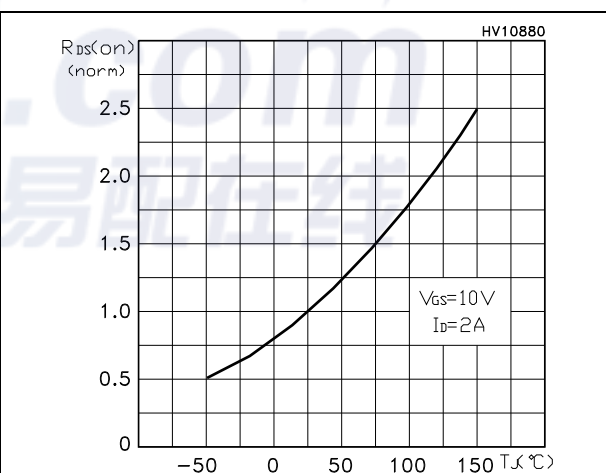
Figure 11. Normalized $R_{DS(on)}$ vs temperature

Figure 12. Source-drain diode forward characteristic

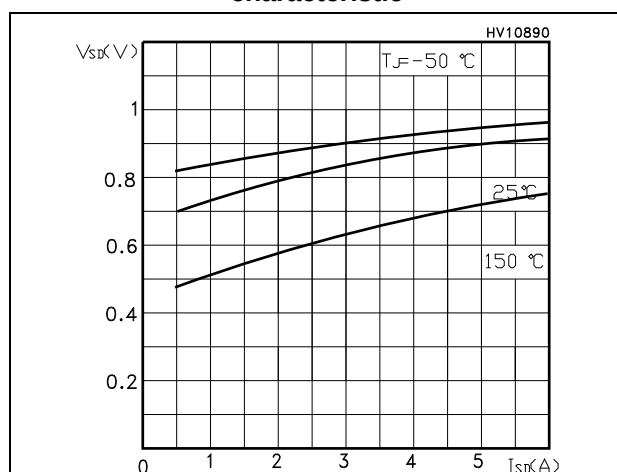
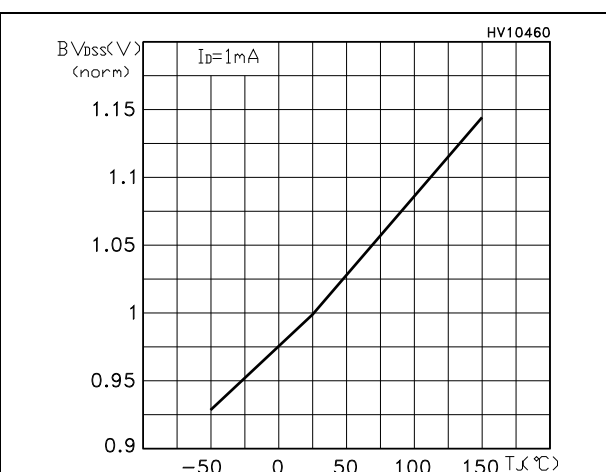
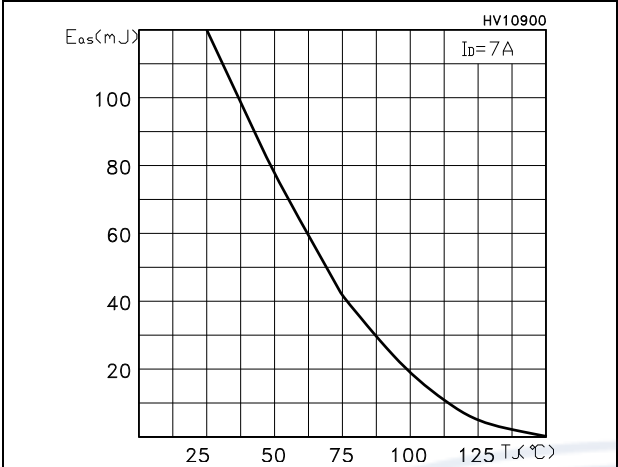
Figure 13. Normalized V_{DS} vs temperature

Figure 14. Avalanche energy vs temperature



3 Test circuits

Figure 15. Switching times test circuit for resistive load

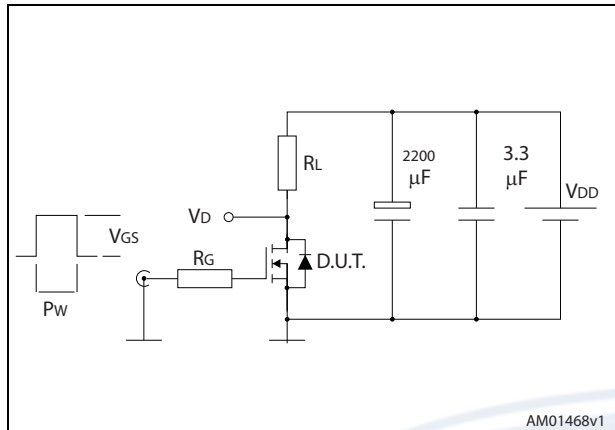


Figure 16. Gate charge test circuit

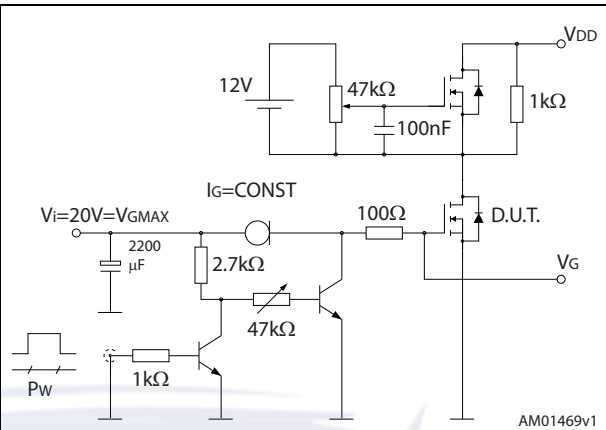


Figure 17. Test circuit for inductive load switching and diode recovery times

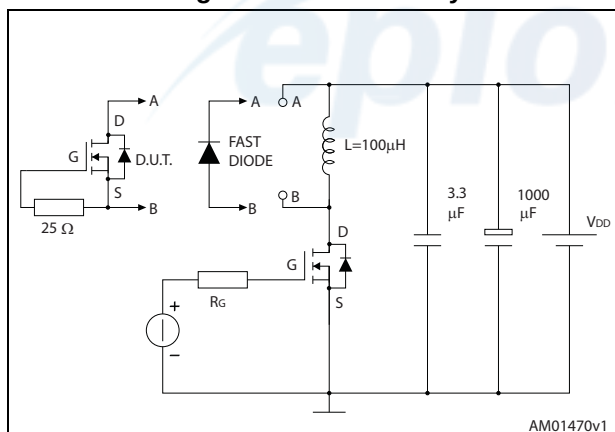


Figure 18. Unclamped inductive load test circuit

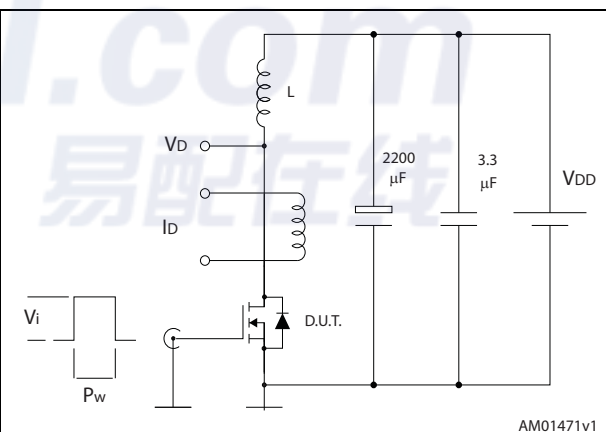


Figure 19. Unclamped inductive waveform

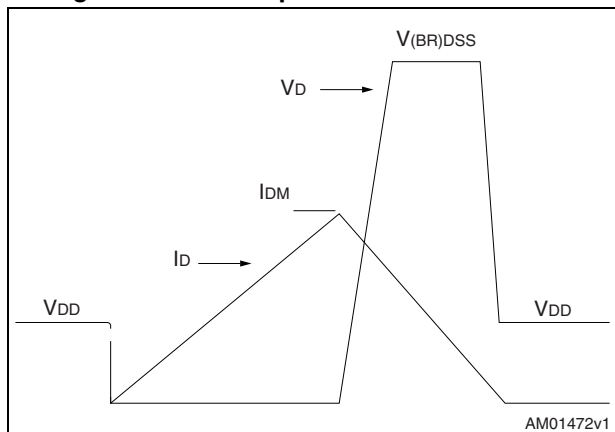
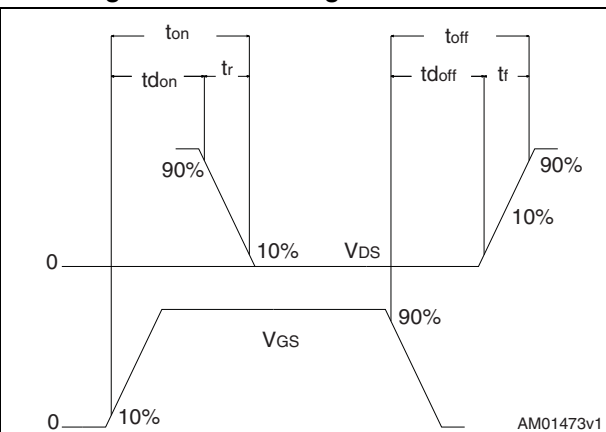


Figure 20. Switching time waveform



4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.



Table 9. D²PAK (TO-263) mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	0.03		0.23
b	0.70		0.93
b2	1.14		1.70
c	0.45		0.60
c2	1.23		1.36
D	8.95		9.35
D1	7.50		
E	10		10.40
E1	8.50		
e		2.54	
e1	4.88		5.28
H	15		15.85
J1	2.49		2.69
L	2.29		2.79
L1	1.27		1.40
L2	1.30		1.75
R		0.4	
V2	0°		8°

Figure 21. D²PAK (TO-263) drawing

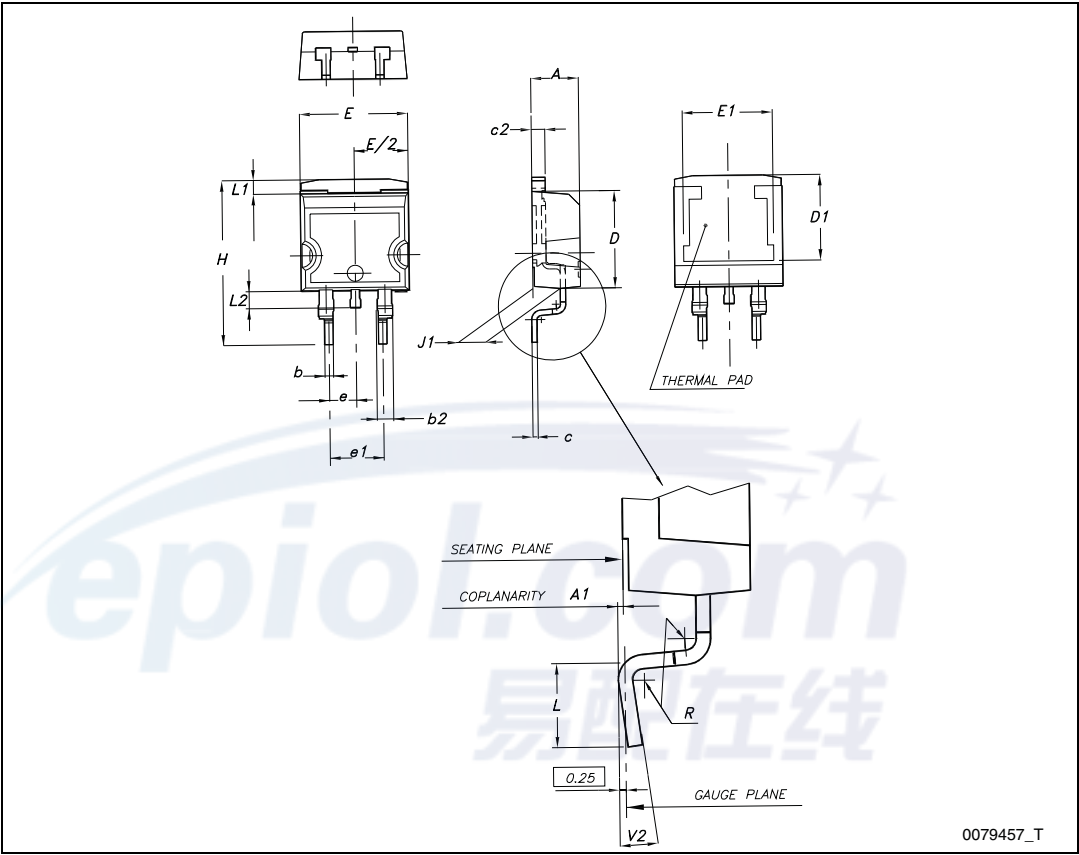
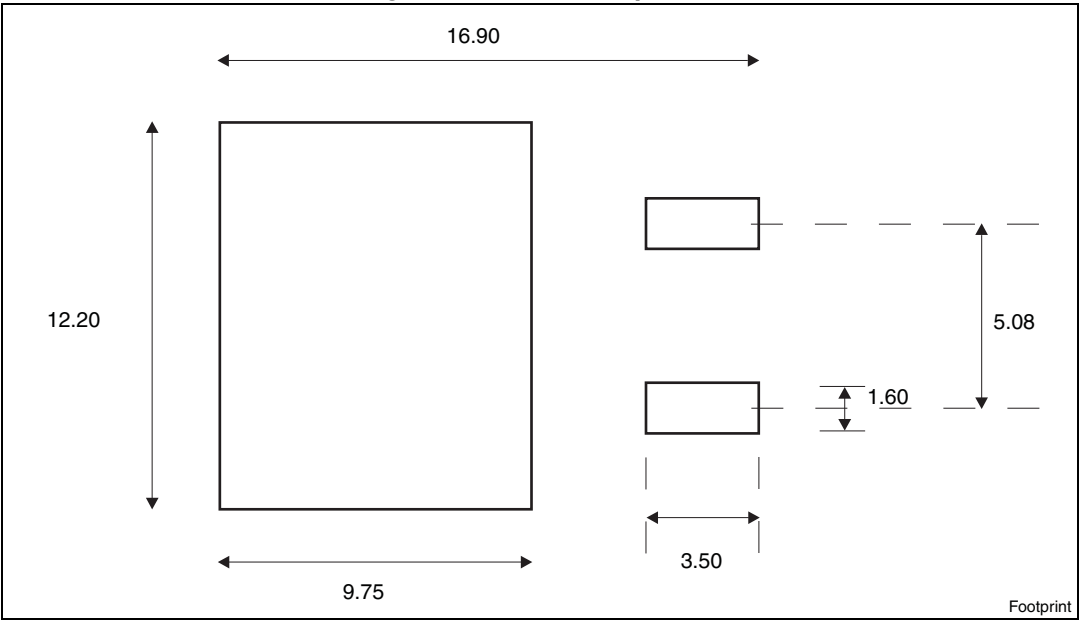


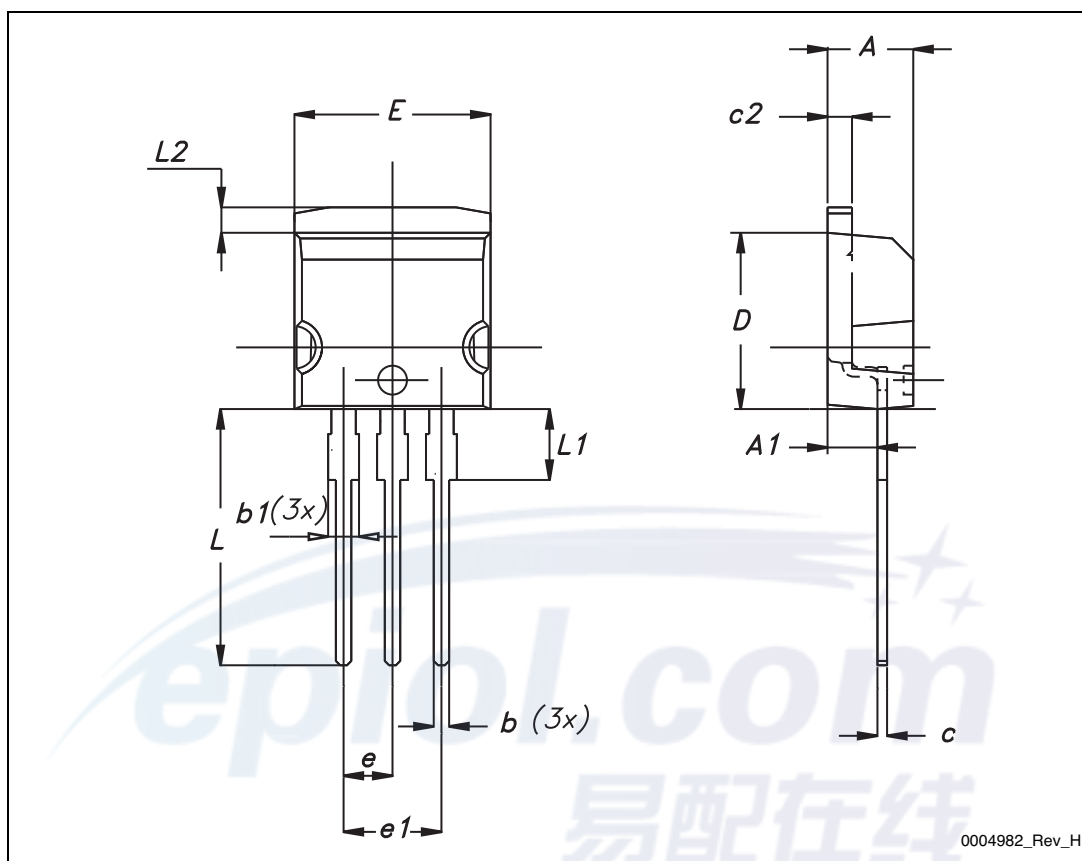
Figure 22. D²PAK footprint^(a)



a. All dimension are in millimeters

Table 10. I²PAK (TO-262) mechanical data

DIM.	mm.		
	min.	typ	max.
A	4.40		4.60
A1	2.40		2.72
b	0.61		0.88
b1	1.14		1.70
c	0.49		0.70
c2	1.23		1.32
D	8.95		9.35
e	2.40		2.70
e1	4.95		5.15
E	10		10.40
L	13		14
L1	3.50		3.93
L2	1.27		1.40

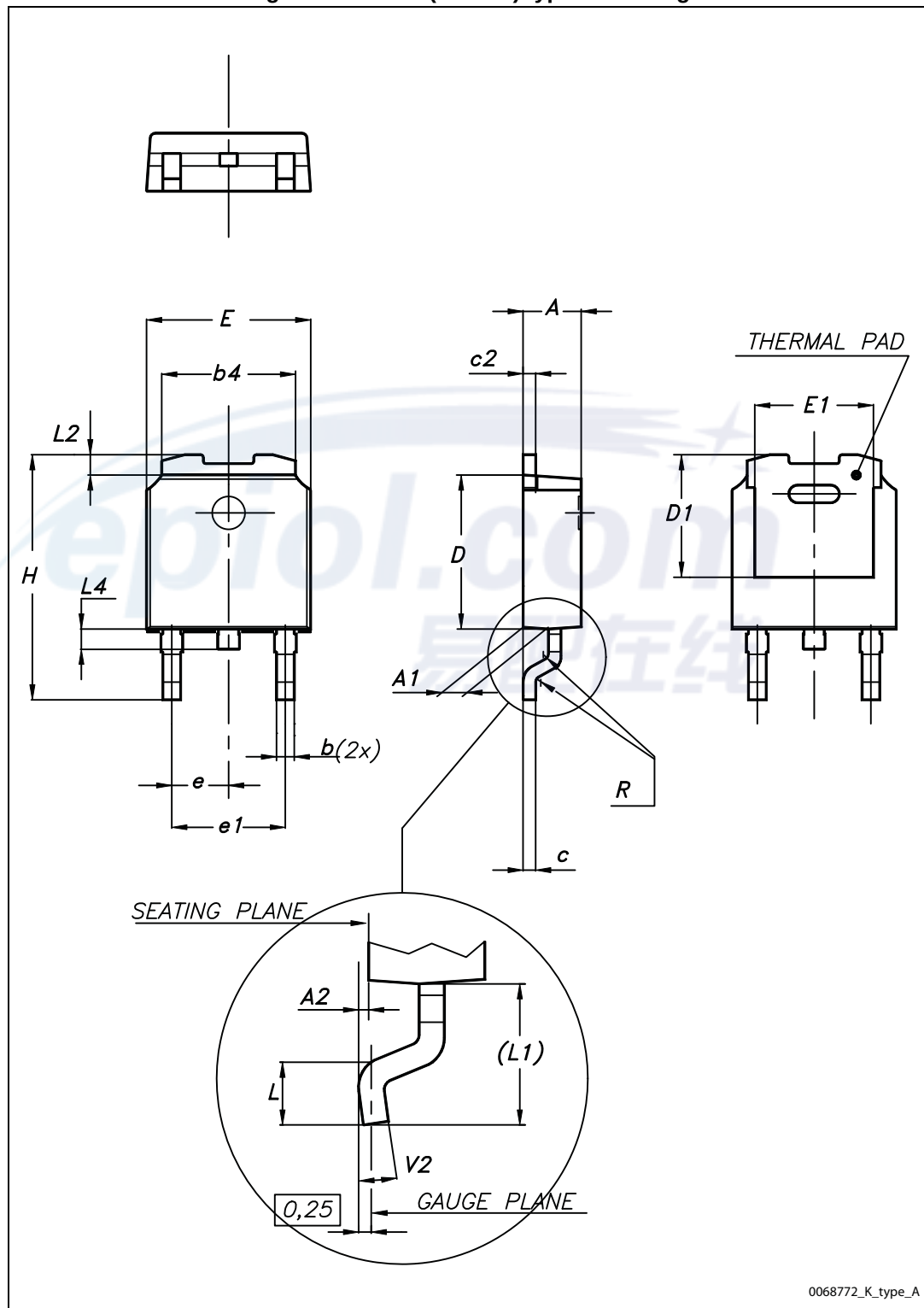
Figure 23 I²PAK (TO-262) drawing

0004982_Rev_H

Table 11. DPAK (TO-252) type A mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1		5.10	
E	6.40		6.60
E1		4.70	
e		2.28	
e1	4.40		4.60
H	9.35		10.10
L	1.00		1.50
(L1)		2.80	
L2		0.80	
L4	0.60		1.00
R		0.20	
V2	0°		8°

Figure 24. DPAK (TO-252) type A drawing



0068772_K_type_A

Table 12. DPAK (TO-252) type E mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.18		2.39
A2			0.13
b	0.65		0.884
b4	4.95		5.46
c	0.46		0.61
c2	0.46		0.60
D	5.97		6.22
D1	5.21		
E	6.35		6.73
E1	4.32		
e		2.286	
e1		4.572	
H	9.94		10.34
L	1.50		1.78
L1		2.74	
L2	0.89		1.27
L4			1.02

Figure 25. DPAK (TO-252) type E drawing

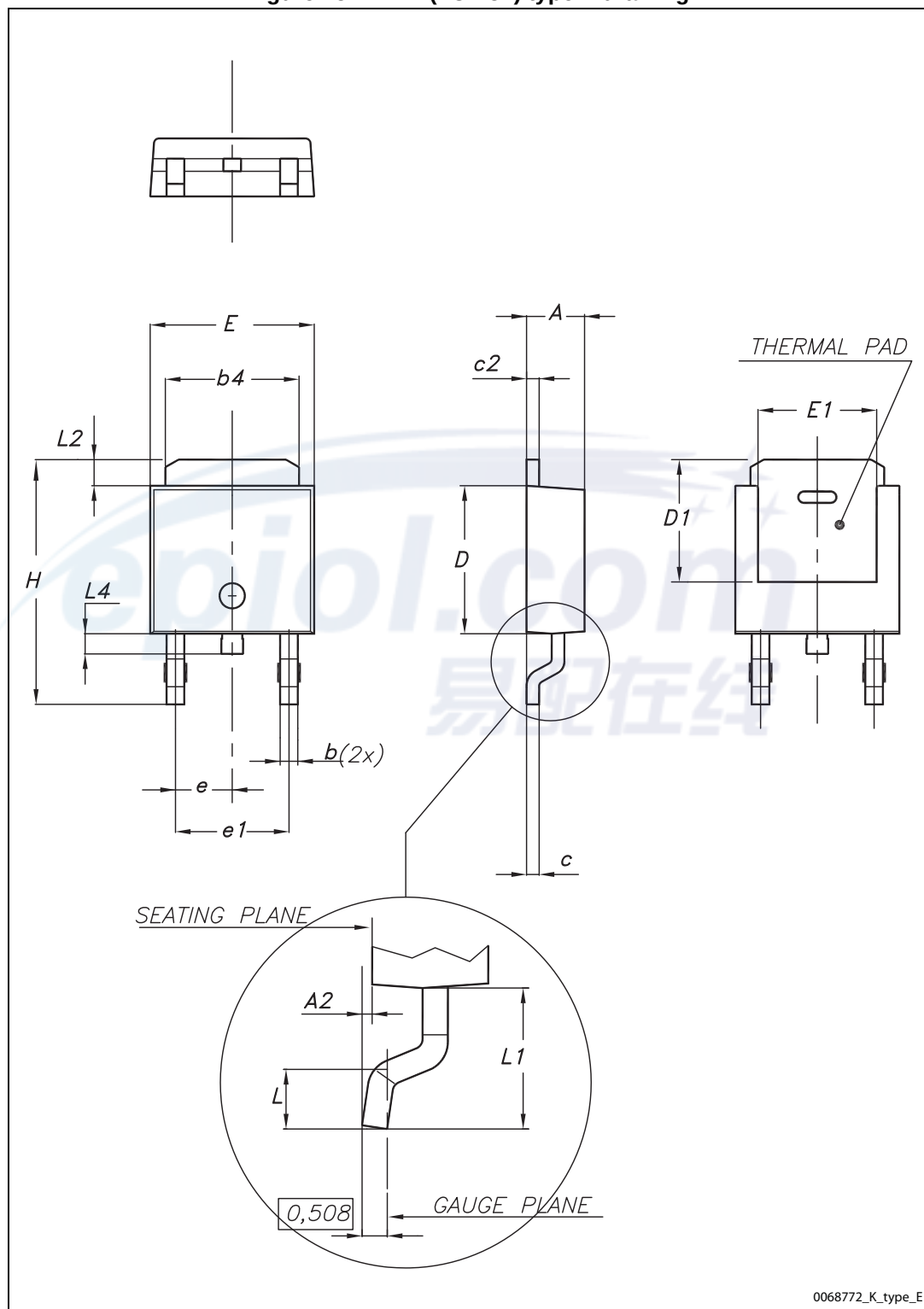
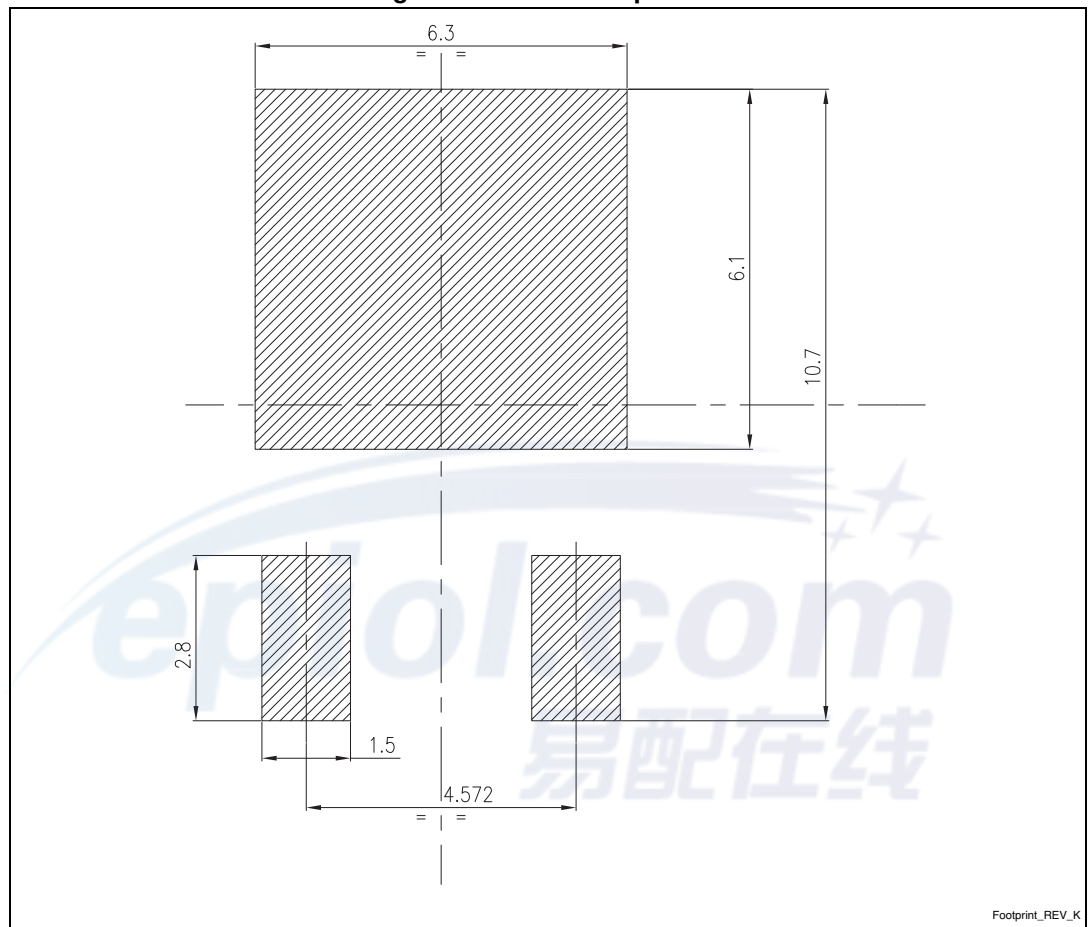


Figure 26. DPAK footprint (b)

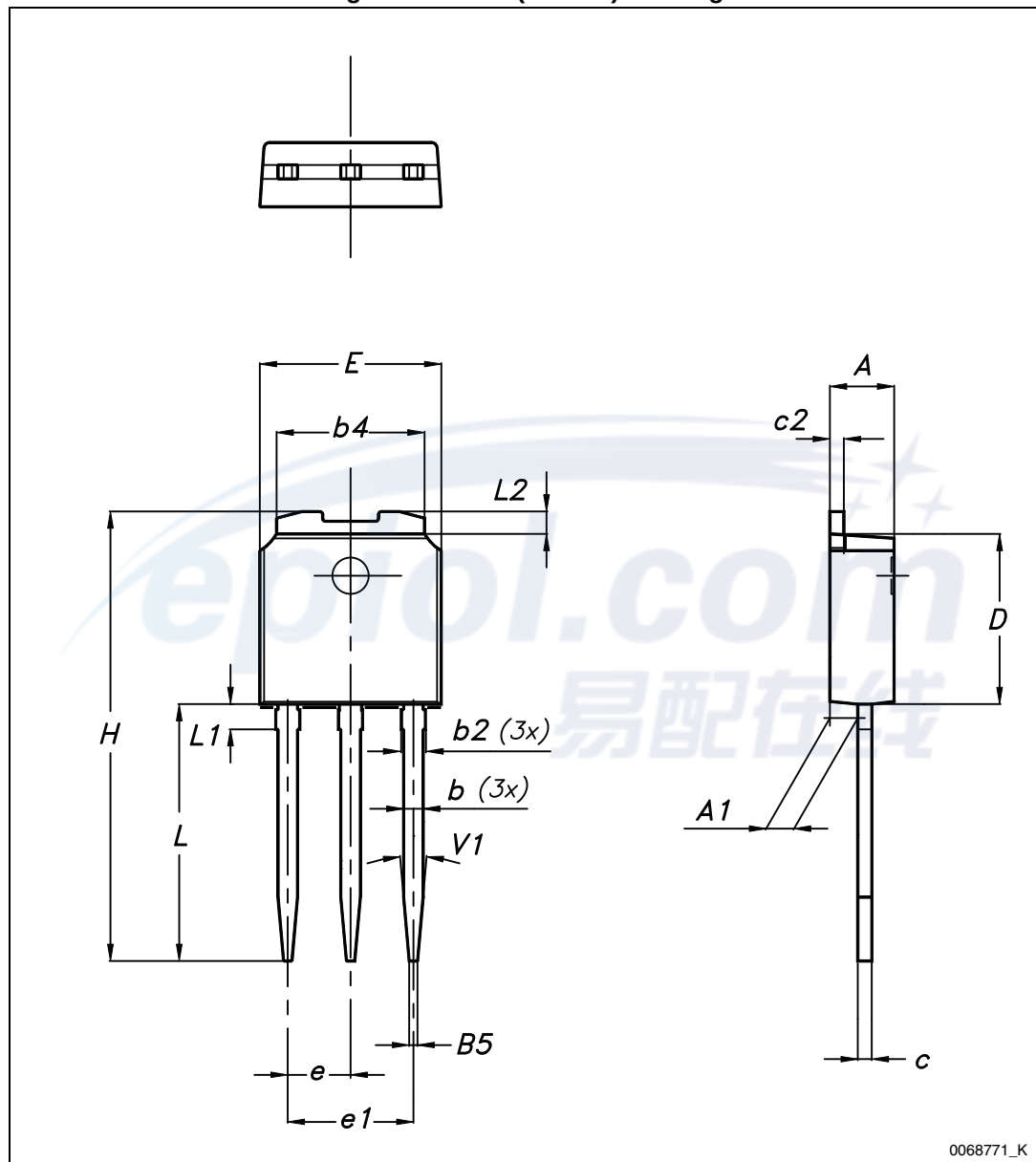


b. All dimensions are in millimeters

Table 13. IPAK (TO-251) mechanical data

DIM	mm.		
	min.	typ.	max.
A	2.20		2.40
A1	0.90		1.10
b	0.64		0.90
b2			0.95
b4	5.20		5.40
B5		0.30	
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
E	6.40		6.60
e		2.28	
e1	4.40		4.60
H		16.10	
L	9.00		9.40
L1	0.80		1.20
L2		0.80	1.00
V1		10°	

Figure 27. IPAK (TO-251) drawing



5 Packaging mechanical data

Table 14. D²PAK (TO-263) tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	10.5	10.7	A		330
B0	15.7	15.9	B	1.5	
D	1.5	1.6	C	12.8	13.2
D1	1.59	1.61	D	20.2	
E	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	T		30.4
P0	3.9	4.1			
P1	11.9	12.1	Base qty		1000
P2	1.9	2.1	Bulk qty		1000
R	50				
T	0.25	0.35			
W	23.7	24.3			

Table 15. DPAK (TO-252) tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	6.8	7	A		330
B0	10.4	10.6	B	1.5	
B1		12.1	C	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	T		22.4
K0	2.55	2.75			
P0	3.9	4.1		Base qty.	2500
P1	7.9	8.1		Bulk qty.	2500
P2	1.9	2.1			
R	40				
T	0.25	0.35			
W	15.7	16.3			

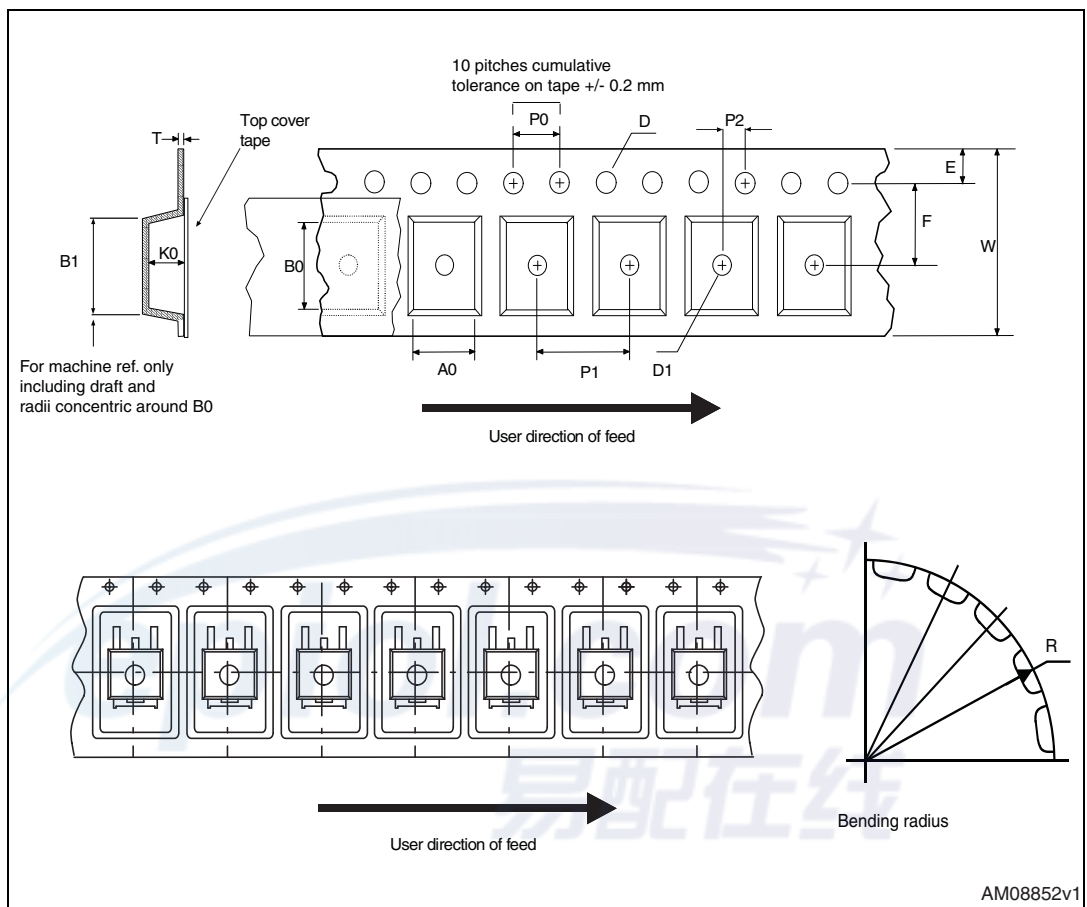
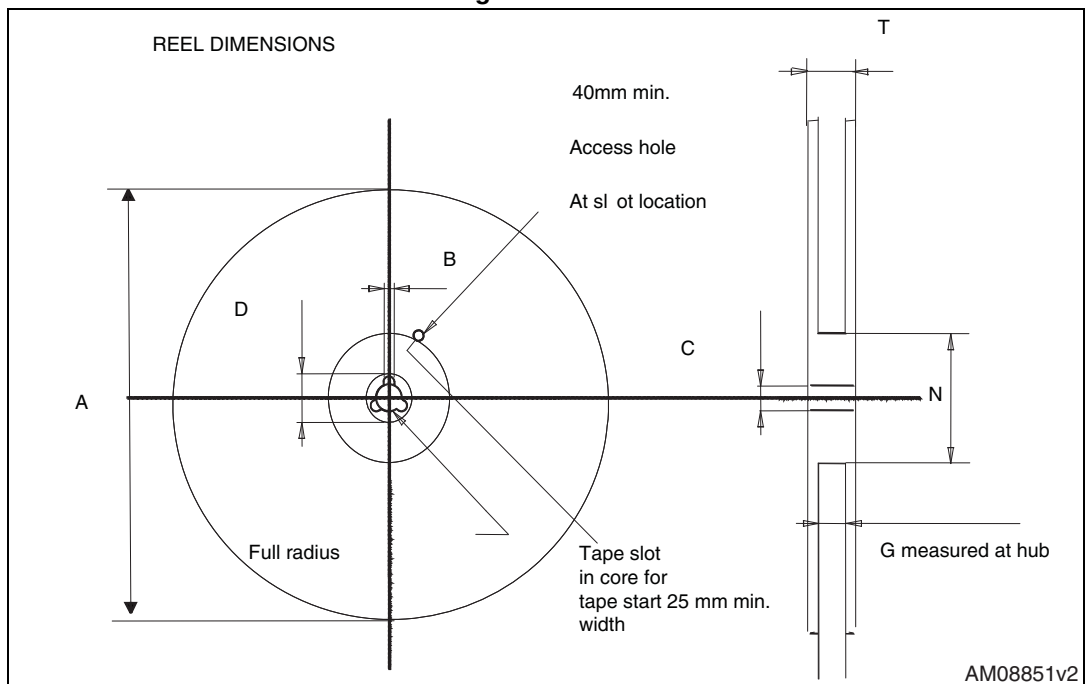


Figure 29. Reel



6 Revision history

Table 16. Document revision history

Date	Revision	Changes
25-Oct-2006	4	Document reformatted no content change.
04-Mar-2008	5	Modified TO-220 and TO-220FP mechanical data.
16-Apr-2008	6	Minor text changes to improve readability.
11-Jul-2011	7	Updated package mechanical data Section 4 and packaging mechanical data Section 4 .
18-Jul-2013	8	– Minor text changes – The part numbers STP4NK60Z and STP4NK60ZFP have been moved to a separate datasheet – Updated: Section 4: Package mechanical data and Section 4: Package mechanical data

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